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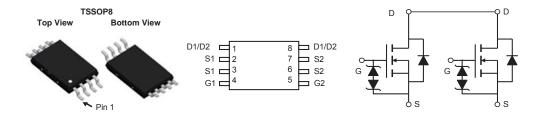
Dual N-Channel 20 V MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A)	Q _g (Typ.)			
20	0.0095 at V _{GS} = 4.5 V	11 ^a	14 5			
20	0.0113 at V _{GS} = 2.5 V	9	14.5			

FEATURES

- · Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET® Power MOSFET
- 100 % R_g Tested 100 % UIS Tested
- Compliant to RoHS Directive 2002/95/EC
- ESD Protected 2KV HBM





ABSOLUTE MAXIMUM RATINGS T_A :	= 25 °C, unless other	wise noted		
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V_{DS}	20	V	
Gate-Source Voltage	V_{GS}	± 12	v	
	T _C = 25 °C		11	
Continuous Drain Current (T = 150 °C)	T _C = 70 °C	,	9.9	
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	ID	10.5 ^{b, c}	
	T _A = 70 °C		8.2 ^{b, c}	
Pulsed Drain Current (10 µs Pulse Width)	·	I _{DM}	30	۸
Source-Drain Current Diode Current	T _C = 25 °C	I _S	2.7	А
	T _A = 25 °C		1.6 ^{b, c}	
Pulsed Source-Drain Current	I _{SM}	30		
Single Pulse Avalanche Current	e Pulse Avalanche Current		10	
Single Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	10	
	T _C = 25 °C	P _D	3.25	
Marian an Danian Dissipation	T _C = 70 °C		2.10	W
Maximum Power Dissipation	T _A = 25 °C		2.0 ^{b, c}	VV
	T _A = 70 °C		1.25 ^{b, c}	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Тур.	Max.	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	45	62.5	°C/W	
Maximum Junction-to-Foot (Drain)	Steady-State	R _{thJF}	29	38	<i>5/</i> V V	

Notes:

- a. Based on T_C = 25 °C.
 b. Surface mounted on 1" x 1" FR4 board.
- d. Maximum under steady state conditions is 120 °C/W.

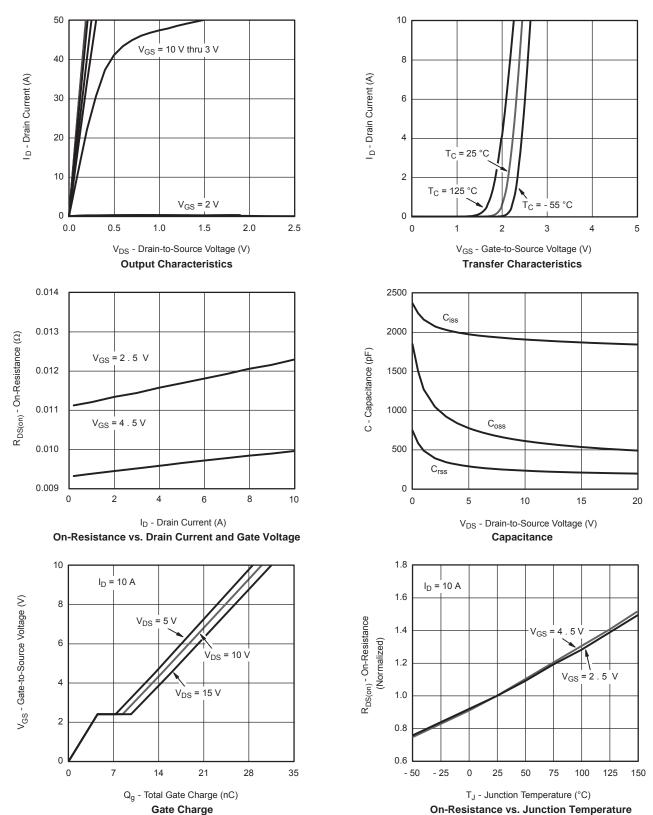
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Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	•			•			
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA	20			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		20		\//90	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 5.8		mV/°C	
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA	0.6		1.2	V	
Gate-Body Leakage	I _{GSS}	V _{DS} = 0 V, V _{GS} = ± 8 V		İ	10	uA	
Zara Cata Valta da Brain Comunit	,	V _{DS} = 16 V, V _{GS} = 0 V			1	μА	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 16 V, V _{GS} = 0 V, T _J = 55 °C			10		
On-State Drain Current ^b	I _{D(on)}	V _{DS} = 5 V, V _{GS} = 10 V	11			Α	
D : 0	_	V _{GS} = 4.5 V, I _D = 10 A		0.0095	0.0119	Ω	
Drain-Source On-State Resistance ^b	R _{DS(on)}	V _{GS} = 2.5 V, I _D = 8 A		0.0113	0.0148		
Forward Transconductance ^b	9 _{fs}	V _{DS} = 15 V, I _D = 10 A		50		S	
Dynamic ^a	•			•			
Input Capacitance	C _{iss}			2110		pF	
Output Capacitance	C _{oss}	V _{DS} = 10 V, V _{GS} = 0 V, I _D = 1 MHz		926			
Reverse Transfer Capacitance	C _{rss}			235			
Total Gate Charge	Qg	V _{DS} = 10 V, V _{GS} = 10 V, I _D = 10 A		30	45	nC	
				14.5	22		
Gate-Source Charge	Q _{gs}	V _{DS} = 10 V, V _{GS} = 4.5 V, I _D = 10 A		4.5			
Gate-Drain Charge	Q _{gd}			3.9		1	
Gate Resistance	R _g	f = 1 MHz	0.4	1.4	2.8	Ω	
Turn-On Delay Time	t _{d(on)}			8	16		
Rise Time	t _r	$V_{DD} = 10 \text{ V, R}_{L} = 1 \Omega$		15	30		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		24	45	1	
Fall Time	t _f			9	18		
Turn-On Delay Time	t _{d(on)}			18	35	ns	
Rise Time	t _r	$V_{DD} = 10 \text{ V, R}_{I} = 1 \Omega$		24	45		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		26	50	1	
Fall Time	t _f			13	26	1	
Drain-Source Body Diode Characterist	ics			•			
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			2.7		
Pulse Diode Forward Current ^a	I _{SM}	-		1	30	A	
Body Diode Voltage	V _{SD}	I _S = 3 A		0.70	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}	-		20	40	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	N-Channel		10	20	nC	
Reverse Recovery Fall Time	t _a	I _F = 10 A, dl/dt = 100 A/μs, T _J = 25 °C		11		_	
Reverse Recovery Rise Time	t _b			9		nS	

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

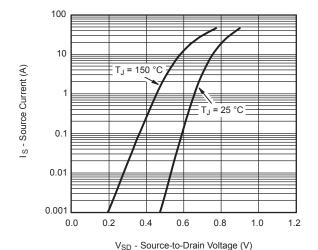


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

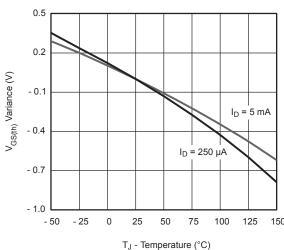




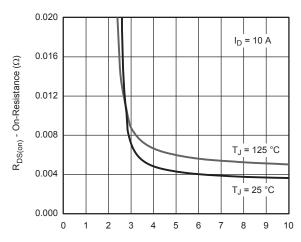
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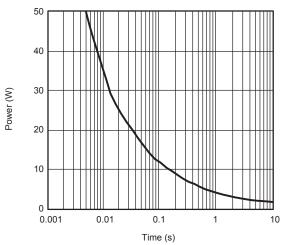
Source-Drain Diode Forward Voltage



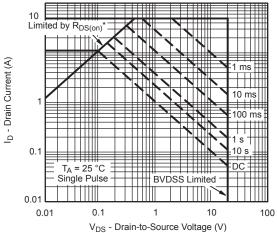
Threshold Voltage



 $\label{eq:VGS} \mbox{V}_{GS} \mbox{ - Gate-to-Source Voltage (V)}$ On-Resistance vs. Gate-to-Source Voltage



Single Pulse Power, Junction-to-Ambient

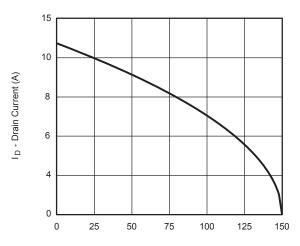


* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

Safe Operating Area, Junction-to-Ambient

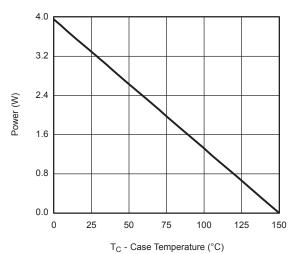
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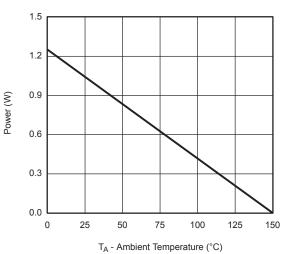


T_C - Case Temperature (°C)

Current Derating*



Power Derating, Junction-to-Foot

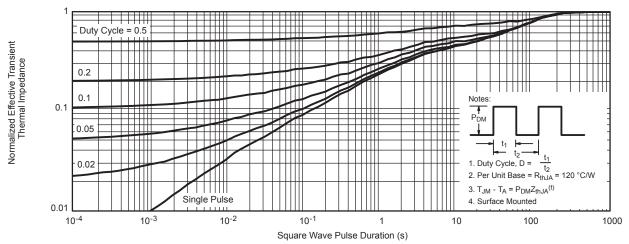


Power Derating, Junction-to-Ambient

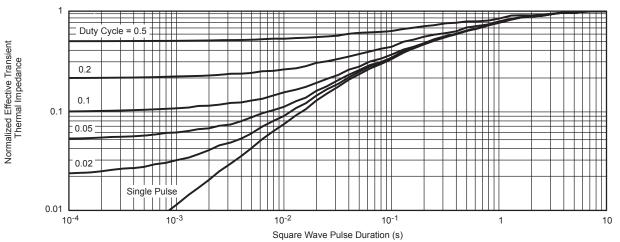
 $^{^*}$ The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Ambient



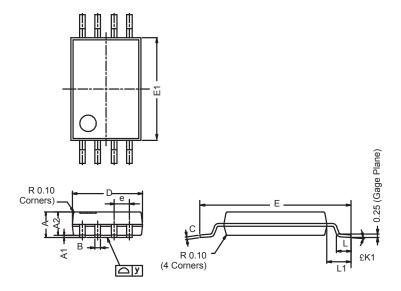
Normalized Thermal Transient Impedance, Junction-to-Foot





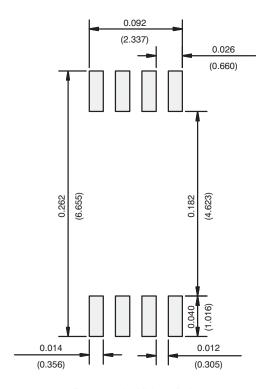
TSSOP: 8-LEAD

JEDEC Part Number: MO-153



	MILLIMETERS			
Dim	Min	Nom	Max	
Α	_	-	1.20	
A ₁	0.05	0.10	0.15	
A ₂	0.80	1.00	1.05	
В	0.19	0.28	0.30	
С	-	0.127	-	
D	2.90	3.00	3.10	
Е	6.20	6.40	6.60	
E ₁	4.30	4.40	4.50	
е	-	0.65	_	
L	0.45	0.60	0.75	
L ₁	0.90	1.00	1.10	
Υ	_	-	0.10	
£ K1	0°	3°	6°	
ECN: S-03946—Rev. G, 09-Jul-01 DWG: 5844				

RECOMMENDED MINIMUM PADS FOR TSSOP-8



Recommended Minimum Pads Dimensions in Inches/(mm)



Din-Tek SEMICONDUCTOR

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